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generalization of the conventional competitive analysis and extra-resource analysis for on-line algorithms. We apply this analysis to study on-line schedulers for stream merging in two different video-on-demand (VOD) systems, which are based on two common approaches, namely, piggybacking and skimming. Our new analysis, in its simplest form, reveals a 3-competitive algorithm for stream merging based on skinni ...

4 The Generation of Minimal Trees with a Steiner Topology

Shi-Kuo Chang


October 1972 **Journal of the ACM (JACM)**, Volume 19 Issue 4

Full text available:  [pdf\(704.77 KB\)](#) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

5 A study of source-level compiler algorithms for automatic construction of pre-execution code

Dongkeun Kim, Donald Yeung

August 2004 **ACM Transactions on Computer Systems (TOCS)**, Volume 22 Issue 3

Full text available:  [pdf\(1.55 MB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)


Pre-execution is a promising latency tolerance technique that uses one or more helper threads running in spare hardware contexts ahead of the main computation to trigger long-latency memory operations early, hence absorbing their latency on behalf of the main computation. This article investigates several source-to-source C compilers for extracting pre-execution thread code automatically, thus relieving the programmer or hardware from this onerous task. We present an aggressive profile-driven co ...

Keywords: Data prefetching, memory-level parallelism, multithreading, pre-execution, prefetch conversion, program slicing, speculative loop parallelization

6 Dynamic metrics for java

Bruno Dufour, Karel Driesen, Laurie Hendren, Clark Verbrugge

October 2003 **ACM SIGPLAN Notices , Proceedings of the 18th annual ACM SIGPLAN conference on Object-oriented programming, systems, languages, and applications**, Volume 38 Issue 11

Full text available:  [pdf\(222.57 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

In order to perform meaningful experiments in optimizing compilation and run-time system design, researchers usually rely on a suite of benchmark programs of interest to the optimization technique under consideration. Programs are described as *numeric*, *memory-intensive*, *concurrent*, or *object-oriented*, based on a qualitative appraisal, in some cases with little justification. We believe it is beneficial to quantify the behaviour of programs with a concise and precisely ...

Keywords: Java, dynamic metrics, execution traces, optimization, profiling, program analysis, software metrics

7 System papers: exploration and retrieval tools: Sketch-based retrieval of ClipArt drawings

Manuel Fonseca, Bruno Barroso, Pedro Ribeiro, Joaquim Jorge

May 2004 **Proceedings of the working conference on Advanced visual interfaces**

Full text available:  [pdf\(151.46 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

These days there are a lot of vector drawings available for people to integrate into


documents. These come in a variety of formats, such as Corel, Postscript, CGM, WMF and recently SVG. Typically, such ClipArt drawings tend to be archived and accessed by categories (e.g. food, shapes, transportation, etc.). However, to find a drawing among hundreds of thousands is not an easy task. While text-driven attempts at classifying image data have been recently supplemented with query-by-image content, ...

Keywords: drawing simplification, sketch and content-based retrieval

8 Highly available systems for database applications

Won Kim

March 1984 **ACM Computing Surveys (CSUR)**, Volume 16 Issue 1

Full text available:  pdf(2.43 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#), [review](#)

As users entrust more and more of their applications to computer systems, the need for systems that are continuously operational (24 hours per day) has become even greater. This paper presents a survey and analysis of representative architectures and techniques that have been developed for constructing highly available systems for database applications. It then proposes a design of a distributed software subsystem that can serve as a unified framework for constructing database applica ...

9 Semiconductor technology: trends and implications

Dileep P. Bhandarkar, J. Egil Juliussen

August 1978 **ACM SIGARCH Computer Architecture News**, Volume 7 Issue 1

Full text available:  pdf(748.60 KB)

Additional Information: [full citation](#), [references](#)

10 The Bell Telephone Laboratories automatic graphic schematic drawing program

William R. DeHaan

January 1966 **Proceedings of the SHARE design automation project**

Full text available:  pdf(924.56 KB)


Additional Information: [full citation](#), [abstract](#), [citations](#), [index terms](#)

This paper describes an Automatic Schematic Drawing program developed at Bell Telephone Laboratories. This computer drawing program is written in the Macro Assembly Language. It is designed to permit the automatic generation of schematic drawings for digital equipment. Data—regarding electrical components and connectivity—is extracted from a master design file and processed by the program on either the IBM 7090/94 or IBM 7040/44 computer. Graphic output is provided by the Stromb ...

11 Fault-tolerance and fault-intolerance: Complementary approaches to reliable computing

Algirdas Avižienis

April 1975 **ACM SIGPLAN Notices , Proceedings of the international conference on Reliable software**, Volume 10 Issue 6

Full text available:  pdf(768.57 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

Two complementary methods which are employed in order to assure reliable computing are fault-intolerance and fault-tolerance. Fault-intolerance depends on the elimination of the causes of unreliability prior to the start of the computing process while fault-tolerance employs protective redundancy during the computing process in order to detect and to correct unreliable functioning. A balanced allocation of reliability resources between the two metho ...

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	Type	Hits	Search Text	Dbs	Time Stamp	Com ments	Error Defi nitions	Error s	Ref #
1	IS&R	4	((("6282326") or ("6317223")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM; TDB	2004/11/16 08:43				S1
2	BRS	8	("4649436" "5214470" "5223951" "5436979" "5583659" "5974194" "6035072" "6125213").PN.	US-PGPUB; USPAT; USOCR	2004/11/15 14:43				S2
3	BRS	0	("6317223").URPN.	USPAT	2004/11/15 15:05				S3
4	BRS	2	("6282326").URPN.	USPAT	2004/11/15 15:05				S4
5	BRS	7	("4912559" "5054098" "5214470" "5583659" "5949901" "5956435" "6035072").PN.	US-PGPUB; USPAT; USOCR	2004/11/15 15:14				S5
6	BRS	1	((vertical adj1 line) near3 (remoc\$3 delet\$3 detect\$3)) with real\$1time	US-PGPUB; USPAT; USOCR	2004/11/15 15:16				S6
7	BRS	1	((vertical adj1 line) near3 (remoc\$3 delet\$3 detect\$3)) same real\$1time	US-PGPUB; USPAT; USOCR	2004/11/15 15:16				S7
8	BRS	1	((vertical adj1 line) near3 (remov\$3 delet\$3 detect\$3)) same real\$1time	US-PGPUB; USPAT; USOCR	2004/11/15 15:17				S8
9	BRS	605	((vertical adj1 line) near3 (remov\$3 delet\$3 detect\$3))	US-PGPUB; USPAT; USOCR	2004/11/15 15:42				S9
10	BRS	10	(vertical adj1 line adj1 removal)	US-PGPUB; USPAT; USOCR	2004/11/15 15:21				S10
11	BRS	1	S9 same (difference with histogram)	US-PGPUB; USPAT; USOCR	2004/11/15 15:23				S11
12	BRS	20	S9 with difference	US-PGPUB; USPAT; USOCR	2004/11/15 15:23				S12
13	BRS	415	((vertical adj1 line) near3 (detect\$3))	US-PGPUB; USPAT; USOCR	2004/11/15 15:44				S13
14	BRS	97	((vertical adj1 line) adj1 (detect\$3))	US-PGPUB; USPAT; USOCR	2004/11/15 16:26				S14
15	BRS	18	S13 with difference	US-PGPUB; USPAT; USOCR	2004/11/15 15:44				S15

	Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nition	Error s	Ref #
16	BRS	72440	(line near3 detect\$3)	US-PGPUB; USPAT; USOCR	2004/11/15 16:32				S16
17	BRS	14740	(line adj1 detect\$3)	US-PGPUB; USPAT; USOCR	2004/11/15 16:27				S17
18	BRS	563	(line adj1 detect\$3) with difference	US-PGPUB; USPAT; USOCR	2004/11/16 10:10				S18
19	BRS	5	(line adj1 detect\$3) with difference with histogram	US-PGPUB; USPAT; USOCR	2004/11/15 16:27				S19
20	BRS	11	(line near3 detect\$3) with difference with histogram	US-PGPUB; USPAT; USOCR	2004/11/15 16:36				S20
21	BRS	17	(line near3 detect\$3) with difference with project\$3	US-PGPUB; USPAT; USOCR	2004/11/15 16:36				S21
22	BRS	2	((line adj1 scratch adj1 removal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/15 16:48				S22
23	BRS	2954	382/170,174,202,270,275,289,304.cds.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/17 10:47				S23
24	BRS	1245	358/463;700/4,5.cds.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 08:48				S24
25	BRS	4093	S23 or S24	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 08:49				S25
26	BRS	489	S25 and ((line near3 (detect\$3 remov\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 08:49				S26
27	BRS	43	S26 and ((binari\$6 bi\$1level black\$5white) adj1 image)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 08:51				S27

	Type	Hits	Search Text	DBs	Time Stamp	Com ments	Error Defi nitions	Error s	Ref #
28	BRS	38	S27 and @ad<"20020116"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 10:14				S28
29	BRS	59177	((images with ("XOR" exclusive\$1OR difference))	US-PGPUB; USPAT; USOCR	2004/11/16 10:13				S29
30	BRS	148	S26 and S29	US-PGPUB; USPAT; USOCR	2004/11/16 10:13				S30
31	BRS	133	S30 and @ad<"20020116"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 10:15				S31
32	IS&R	2	("5467410").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 14:00				S32
33	BRS	722	348/241,246,247.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 14:29				S33
34	BRS	12	S33 and ((vertical adj1 (line streak)) with (replac\$5 remov\$3 detect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 14:30				S34
35	BRS	7431	image same ((selective\$2 alternate\$2 alternative\$2) near3 (output\$4 replace\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:34				S35
36	BRS	15154	((line same ((selective\$2 alternate\$2 alternative\$2) near3 (output\$4 replace\$5)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:34				S36
37	BRS	4380	((line same ((selective\$2 alternate\$2 alternative\$2) adj1 (output\$4 replace\$5)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:35				S37
38	BRS	3998	((line same ((selective\$2 alternate\$2 alternative\$2) adj1 (output\$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:35				S38

	Type	Hits	Search Text	Dbs	Time Stamp	Com ments	Error Defi nitions	Error s	Ref #
39	BRS	1968	((line same ((selective\$2) adj1 (output\$4))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:35				S39
40	BRS	1282	((line with ((selective\$2) adj1 (output\$4))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:35				S40
41	BRS	468	((pixel with ((selective\$2) adj1 (output\$4))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:36				S41
42	BRS	29	((correct\$3 same (pixel with (selective\$2 adj1 output\$4))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/16 16:37				S42
43	BRS	119	382/163.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/11/17 10:49				S43

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1 A fast algorithm for plotting and contour filling radiation patterns in three dimensions

Peters, T.J.;

Antennas and Propagation Society International Symposium, 1992. AP-S. 1992 Digest. Held in Conjunction with: URSI Radio Science Meeting and Nuclear EMP Meeting, IEEE, 18-25 July 1992
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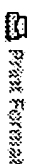
[Abstract]

[PDF Full-Text (196 KB)]

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